ESH and ITRS Impact on Semiconductor Technology Development

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Acknowledgments

- Jim Jewett Intel ESH TWG Chair
- Walter Worth ISMI ESH TWG Co-chair
- Members of the ESH TWG



Impacts of ESH Issues on the Industry

- In the past, ESH issues have negatively impacted semiconductor manufacturers -Ethylene glycol ethers, CFCs, PFCs, PFOS
 - Chemical exposure concerns (and lawsuits)
 - Environmental clean ups (Superfund Sites)
 - Use restriction regulations

Designing for Sustainability allows for early identification of potential ESH issues – Resolve issues before process transfer to high volume manufacturing



What is Sustainable Development?

"Development that meets the needs of the present without compromising the ability of future generations to meet their own needs."

Source: Brundtland Commission, 1987



Why Sustainability Now?

- Semiconductor industry is international.
 - Sites in many regions of the world.
 - Customers in many regions of the world.
- Increased environmental awareness resulting in increased focus on corporate sustainability & responsibility.
 - Company-driven
 - NGOs
 - Shareholders
- While U.S. environmental regulations have changed little in recent years, same is not true of other regions.
- Technologists must ensure products and processes they develop are sustainable.



EU Sustainable Development Strategy Priority Challenges

- Climate change and clean energy.
- Sustainable transport.
- Sustainable production and consumption.
- Public health threats.
- Better management of natural resources.
- Social inclusion, demography, and migration.
- Fighting global poverty.



2007 ESH TWG Participants

- James Beasley ISMI
- Laurie Beu Laurie S. Beu Consulting
- Aimee Bordeaux SEMI
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- Tom Diamond IBM
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- Mike Mocella DuPont
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- Brian Raley AMD
- Farhang Shadman U of AZ
- Mike Sherman FSI International
- Jeffrey Sczechowski ST Microelectronics
- Harry Thewissen NXP Semiconductors
- Tetsu Tomine Seiko-Epson*
- Tim Wooldridge SRC
- Walter Worth Sematech*
- Munetsugu Yamanaka TEL
- Tim Yeakley Texas Instruments

* = ITWG Members





ESH Key Themes for 2007

- Focus on critical chemistry/materials needs
- Improvement of energy efficiency
- "ECO" design of factories and products



Underlying Strategies Built into 2007 ESH Chapter

- Understand (characterize) processes and materials to create a development baseline
- Use materials that are less hazardous or whose byproducts are less hazardous
- Design products and systems (equipment and facilities) that consume less raw material and resources
- Ensure factories are safe for employees (300mm to 450mm transition)



Reorganized Tables

- Chemical/Materials Tables focus on chemical selection
- Process Tables focus on process and tool design
- Facilities Tables (new) focus on support systems and fab level design
- Design for Sustainability & Product Stewardship Table focuses on metrics and sustainable product design and manufacture



Difficult Challenges – Chemicals & Materials Management

7	Table ESH1a ESH Difficu	Evaluation and refinement of				
Difficult Challenges $\geq 22 \text{ nm}$	Summary of Issues	quality, rapid assessment				
	Chemical Assess Evaluet nanomaterials can be utilized environment without delayin Regional differences in regulation	methodologies to ensure that new materials such as nanomaterials				
Chemicals and materials management	and full commercialization Trend towards lowering exposur Chemical Data Availability Inability to forecast/anticipate fu	while protecting human health,				
	Lack of comprehensive ESH data for new, proprietary chemicals and materials to respond to the increasing external and regional requirements on the use of chemicals					
	Chemical Exposure Management Lack of information on how the	t chemicals and materials are used and what process by-products are formed				
	Method to obtain information on how the chemicals and materials are used and what process by-products are formed					



Difficult Challenges – Chemicals & Materials Management

Difficult Challenges ≥ 22 nm	Summary of Issues					
	Chemical Assessment Evaluation and refinement of quality, rapid assessment methodologies to ensure that new materials such as nanomaterials can be utilizenvironment without dela Lack of comprehensive ESH					
Chemicals and materials management	Regional differences in regula and full commercializatio data for new, proprietary ring, Trend towards lowering exposion chemicals and materials to respond to the increasing Chemical Data Availability Inability to forecast/anticipate cexternal and regional respond to the increasing Lack of external and regional external and regional requirements on the use of respond Chemical Exposure Managem Lack of information on how the chemicals and materials are used and what process by-products ormed					

Table ESH1a ESH Difficult Challenges—Near-term



Difficult Challenges – Process & Equipment Management

	Process Chemical Optimization		
		cesses that meet technology demands while reducing impact on human	
	health, stfety and the environme chemical quarter requirements		
	Environment Mana Capability for compone	processes that meet technology	
	Need to understand ESH ch mitigation	demands while reducing impact	
	Need to develop effective manager	on human health, safety, and	
	residues from the manufacturing	the environment, both by using	
	Global Warming Emissions Reduction Need to reduce emissions from proc	more benign materials and by	_
	Water and Energy Conservation	reducing chemical quantity	_
	Need for innovative energy- and wa	requirements through more	
Process and equipment management	Consumables Optimization	· · · · · · · · · · · · · · · · · · ·	
	Need for more efficient utilization o	efficient and cost-effective	
	Byproducts Management		
	Development of improved metrolog	process management	



Difficult Challenges – Process & Equipment Management

Need to develop equipment and processes that meet technology demands while reducing impact on human health, safety and the environment, both through the use of more benign materials, and by reducing					
chemical quantity requirements through more efficient and cost-effective process management					
Environment Management					
Capability for component isolation in waste streams					
Need to understand ESH characteristics of process emissions and by-products to identify the appropriate mitigation					
Need to develop effective management systems to address issues related to hazardous and non-hazardous residues from the manufacturing processes					
Global Warming Emissions Reduction					
Need to reduce emissions from processes using high GWP chemicals					
Water and Energy Conservation					
Need for innovative energy- and water-efficient processes and equipment					
Con Optimization					
of chemicals and materials, and increased reuse and recycling					

Need for innovative energy- and water-efficient processes and equipment

gy for byproduct speciation.



Difficult Challenges – Facilities technology requirements and Sustainability and product stewardship

	Need to reduce use of energy, water, and other utilities.
Facilities technology requirements	Conservation Need for more efficient thermal Need to reduce use of management of cleanrooms and Global Warming Emis facilities systems Need to reduce total CO2 equivalent emissions
Sustainability and product stewardship	Sustainability Metrics Need to identify the elements for defining and measuring the sustainability of a technology generation Design for ESH Need to make ESH a design parameter at the design stage of new equipment, processes and products End-of-Life Disposal/Reclaim Need to design facilities, equipment and products to facilitate re-use/disposal at end of life



Difficult Challenges – Facilities technology requirements and Sustainability and product stewardship

Facilities technology requirements Sustainability and product stewardship	Conservation						
	Need to reduce use of energy, water and other utilities						
	Need for more efficient thermal management of cleanrooms and facilities systems						
	Global Warming Emissions Reduction						
	Need to design energy efficient manuf	Need to identify the					
	Need to reduce total CO ₂ equivalent er	elements for defining and					
	Sustainability Matrice						
	Need to identify the elements for defin		on				
Sustainability and product stawardship	Design for ESH	sustainability of a					
Sustainability and product stewardship	Need to make FSH a design para-		ts				
		technology generation					
	Need to design facilities, equipment and	products to facilitate re-use/disposal at end of life					



Difficult Challenges – Facilities technology requirements and Sustainability and product stewardship

	Conservation						
	Need to reduce use of energy, water and other utilities						
	Need for more efficient thermal management of cleanrooms and facilities systems						
Facilities technology requirements	Global Warming Emissions Reduction						
	Need to design energy efficient manufactu	uring facilities					
	Need to reduce total CO ₂ equivalent emiss						
	Sustainability Metrics	Need to make ESH a design					
	Need to identify the elements for defining						
Sector different and the sector different different	Design for ESH	•					
Sustainability and product stewardship	Need to man	stage of new equipment,					
	End-of-Life Disposal/Reclaim	processes, and products					
	Need to design facilities, equipment and p	processes, and products					



ESH Intrinsic Requirements

Table ESH2a ESH Intrinsic Requirements—Near-term Years

Year of Production	2007	2008	2009	2010	2011	2012	2013	2014	2015
I. Chemicals and Materials Management Te	chnology Requ	lirements	•						•
Chemical risk assessments (environmental, health and safety) defined and completed	10	0%	10	100% 100%					
ESH risk assessment techniques for nano- materials and nano-particles		ssessment dology.		Implement risk assessment methodology.					
II. Process and Equipment Technology Requ	irements								
Energy Consumption									
Total fab tools (kWh/cm ²) [2]		0.40-0.35			0.35-0.30)		0.30-0.25	
Tool energy usage (% of 2005 baseline)		90			80		Functio	onal Area Goals TBD	
Tool total equivalent energy* (% of 2007 baseline)	1	00	80	70					
Water Consumption (driven by sustainable g	rowth and cos	t)	•						
Surface preparation UPW use (% of 2005 baseline)	90			80		75			
Tool UPW usage (% of 2005 baseline)		90			80	80			
Chemical Consumption and Waste Reduction	(driven by en	vironmental s	tewardshi	p and cos	:t)				
Improvement in process chemical utilization (% of 2005 baseline)		90			80			75	
Reduce PFC emission	baseline b	ute reduction y 2010 as ag niconductor	reed to b	y the	Maintain	10% absol	ute reductio	on from 199	5 baselin
Liquid and solid waste reduction (% of 2007 baseline)	1	00	90				75		
Manufacturable solutions exist, and are	being optimi	zed							IONAL SEMAT
Manufacturable solu	tions are kno	own							
Interim solu	tions are kno	own 🔶						MANUFACTU	
Manufacturable solutions	are NOT kno	own						MANOFACTO	
-		-							

ESH Intrinsic Requirements

Worker and Workplace Protection								
Safety screening methodologies for new technologies (e.g., 450mm, EUV lithography, ERM)	Develop methodologies.			Implement methodologies.				
III. Facilities Technology Requirements								
Energy Consumption								
Total fab energy usage (kWh/cm ²)		1.5-1.3		1.3-1.1	1.1-1.0			
Total fab support systems energy usage (kWh/cm ²) [2]	0.8–0.6			0.6–0.5	0.5-0.4			
Reduce total fab energy usage (% of 2007 baseline)	1	100 90		80	70			
Water Consumption								
Net feed water use (liters/cm ²) [2]	15	15 15-12		12-10	10-8			
Fab UPW use (liters/cm ²) [2]	8	8-7	,	7-6	6-4			
Chemical Consumption and Waste Reduction	1		I					
Reduce hazardous liquid waste by recycle/reuse** (% of 2007 baseline)	1	00	90	80	75			
Reduce solid waste by recycle/reuse** (% of 2007 baseline)	1	00	90	80	75			
IV. Sustainability and Product Stewardship R	equirements							
Define environmental footprint metrics for process, equipment, facilities, and products; reduce from baseline year.	Define metrics and baseline.		seline.	90% of baseline 80% of basel				
Integrate ESH priorities into the design process for new processes, equipment, facilities, and products.	Define me	etrics and ba	iseline.		INTERNATIONAL SEMA			
Facilitate end-of-life disposal/reclaim	Define me	etrics and ba	seline.					

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Technology Requirements Tables

- Tables for "Chemicals" and "Processes and Equipment" provide requirements for technology thrusts
 - Interconnect
 - Front End Processing
 - Lithography
 - Assembly & Packaging
 - Emerging Research Materials
- Other tables focus on "Facilities" and "Sustainability"



Table ESH3a Chemicals and Materials Management Technology Requirements—Near-term Years

The Environment, Safety, and Health new chemical screening tool (Chemical Restrictions Table) is linked online

	1						1	1	1			
Year of Production	2007		2008	2009	2010	2011	2012	2013	2014	2015		
Interconnect						_						
Surface preparation	Alternative improved E impacts. M improve cl utilization characteri emissions	ESH laintain or pemical Chara	improved impacts. N	Alternatives with improved ESH impacts. Maintain Alternatives with improved ESH impacts. Maintain or hemical by 10%.					Maintain or ESH impacts. Maintain improve chemical			
Front End Processes		emissi	ions; e	establ	ish			•				
High-κ and metal gate materials	Conduct E Maintain o minimize					r improv itilizatior ninimize		chemica	or improv I utilization I minimize cts	ı* by		
Doping (implantation and diffusion)	Lo	w hz	ant materia	ls		Low	hazard do	opant mate	rials			
Conventional surface preparation (stripping, cleaning, rinsing, drying)	Character emissions baseline.		Maintain or improve chemical usage by 10%.			Maintain or improve chemical usage by 10%.			Maintain or improve chemical usage by 10%.			
Alternative surface preparation methods		entify novel wafer cleaning materials. nduct ESH risk assessment of materials				Maintain or improve chemical usage by 10% and minimize process byproducts			Maintain or improve chemical usage by 10% and minimize process byproducts			

Manufacturable solutions exist, and are being optimized Manufacturable solutions are known

Manufacturable solutions are known

Interim solutions are known



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Manufacturable solutions are NOT known

Table ESH3a Chemicals and Materials Management Technology Requirements—Near-term Years

The Environment, Safety, and Health new chemical screening tool (Chemical Restrictions Table) is linked online

Year of Production	2007	2008	2009	2010	2011	2012	2013	2014	2015				
Interconnect		ł											
Surface preparation	Alternatives with improved ESH impacts. Maintain or improve chemical utilization*; characterize emissions.	H Alternatives with improved ESH Alternative impacts. Maintain ESH impa				Alternatives with improved ESH impacts. Maintain or improve chemical (10%.			nproved ntain or				
Front End Processes							•						
High-κ and metal gate materials	Maintain or i Con						Maintain or i Conduct ESH		nprov zatior iimize		Maintain or improve chemical utilization* by 10% and minimize proce byproducts		n* by
Doping (implantation and diffusion)	LOW				Low	Low hazard dopant materials							
Conventional surface preparation (stripping, cleaning, rinsing, drying)	Characterize mate emissions; e baseline.		10%.	chemica	mprov r usa ge by			i or improv I usage by					
Alternative surface preparation methods		n wafer cleaning materials. H risk assessment of materials						Maintain or improve chemical usage by 10% and minimize process byproducts					

Manufacturable solutions exist, and are being optimized Manufacturable solutions are known Interim solutions are known Manufacturable solutions are NOT known





Table ESH3a Chemicals and Materials Management Technology Requirements—Near-term Years

The Environment, Safety, and Health new chemical screening tool (Chemical Restrictions Table) is linked online

Var of Dualitation	2007	2000	2000	2010	2011	2012	2012	2014	2015	
Year of Production	2007	2008	2009	2010	2011	2012	2013	2014	2015	
Interconnect					_					
Surface preparation	Alternatives with improved ESH impacts. Maintain or improve chemical utilization*; characterize emissions.	Alternative improved impacts. I or improve chemical utilization	ESH Maintain e	ESH impacts. Maintain or improve chemical			Maintain or ESH impacts. M cal improve chemic			
Front End Processes										
High-κ and metal gate materials	Conduct ESH risk asses Maintain or improve che minimize process bypro	Maintain or improve chemical utilization* by 10% and minimize process byproducts				l utilizatior	n* by			
Doping (implantation and diffusion)	Low hazard dop	ant materia	lls	L ^c Maintain or improve					Ve	
Conventional surface preparation (stripping, cleaning, rinsing, drying)	Characterize emissions; establish baseline.	emissions; establish improve cher		Maintain or improchemical and wa					ter	
Alternative surface preparation methods	Identify novel wafer clea Conduct ESH risk asses	Maintain process chemical usage by 10% and minimize process byproducts cnemical usage byproducts byproducts				i usage by imize proc	10%			

Manufacturable solutions exist, and are being optimized Manufacturable solutions are known Interim solutions are known Manufacturable solutions are NOT known





Year of Production	2007	2008	2009	2010	2011	2012	2013	2014	2015	
Lithography	<u>. </u>		<u> </u>		1			1		
193 nm immersion resists	Conduct ESH risk assessment of materials.			Maintain or improve chemical utilization* by 10%.		Maintain or improve chemical utilization* by 10%.				
193 nm immersion fluids	Conduct ESH risk Maintain or assessment of improve chemical materials. utilization by 10%.			Maintain or improve chemical utilization* by 10%.			Maintain or improve chemical utilization* by 10%.			
EUV resists	Conduct ESH risk assessment of materials.				Maintain or improve chemical utilization* by 10%.			Maintain or improve chemical utilization* by 10%.		
Imprint	Conduct ESH risk assessment of materials.			Conduct ESH risk assessment of materials.		Maintain or improve chemical utilization* by 10%.				
PFOS/PFAS** chemicals	PFOS/PFAS	ed / implemented			Non-PFAS materials developed for critical uses in lithography					
Mask making and cleaning	Characterize emissions; establish baseline.	emissions; establish chemical utilization Maintain or improve		Alternatives with improved ESH impacts (PFOS-free). Maintain or improve chemical utilization* by 10%; minimize process byproducts.						
Emerging Research Materials										
Nanomaterials	Conduct ESH risk asses	Conduct ESH risk assessment of materials.					s.			
Biological materials and their waste	Conduct ESH risk asses	Conduct ESH risk assessment of materials.								
Materials for novel logic and memory	Conduct ESH risk asses	sment of n	naterials.	C	Conduct E	SH risk as	sessment		NAL SEMATE	



Chemical Restrictions Screen

Issues & Characterization	Show Stopper	High Restriction Potential	Medium Restriction Potential
List of chemicals or raw materials subject to actual or potential manufacture or use restrictions	Asbestos materials Certain glycol ethers Polychlorinated biphenyls Fully halogenated chlorofluorocarbons (CFCs) Carbon tetrachloride 1,1,1 trichloroethane Halons 1211, 1301, 2402 Hydrobromofluorocarbons (HBFCs) HCFC 141b Polybrominated biphenyls (PBBs) and their ethers/oxides (PBDEs) Cadmium compounds Lead compounds Lead compounds Mercury compounds Hexavalent Chromium compounds Polychlorinated biphenyls (PCB)/ terphenyls (PCT) Polychlorinated naphthalene (PCN) Short chain chlorinated paraffins (C10-13, Cl >50%) Tributyl tin (TBT) and, triphenyl tin (TPT) compounds Certain azo colorants	Hydrochlorofluorocarbons (HCFCs) Perfluorooctyl sulfonates (PFOS) Cadmium compounds Lead compounds Mercury compounds Hexavalent chromium compounds	Perfluorocompounds (PFCs) - SF6 - C4F10 - C2F6 - C5F12 - CF4 - C6F14 - NF3 - C4F8 - CHF3 - C3F8 Hydrofluorocarbons (HFCs) Perfluorooctanoic acid (PFOA) and its salts Certain phthalates Phenols Perfluoroalkyl sulfonates (PFAS) Ethylene oxide Ethylene chloride



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Process and Equipment Technology Requirements

Table ESH4a Process and Equipment Management Technology Requirements—Near-term Years

* The Environment, Safety, and Health new chemical screening tool (Chemical Restrictions Table) is linked online

Year of Production	2007	2008	2009	2010	2011	2012	2013	2014	2015
Interconnect									
Surface preparation	Establish baseline for chemical and water usage.; characterize emissions			hemicals and water usage from baseline			Additional 2% reduction in chemicals and water usage per year; recycle/reclaim		
Front End Processes	E	nergy	officia	nt cla	ane				
Surface preparation (stripping, cleaning, rinsing)	ESH-Inenaly wa	rocess			i i i	clean and rir anufacturing		ses and to	ols
	ernissions,	xhaust ptimiz		· · · · · · · · · · · · · · · · · · ·		e chemical n* by 10%			e chemical n* by 10%
	Energy efficient cle exhaust flow rate			Energy e	efficient clea	an processe optimized	s (optimize d heaters)	ed exhaust	flow rates,
Alternative surface preparation methods	Identify novel wafer and equipment. Ch establish water and baselines. Conduct	nissions; age	Novel wafer cleaning technologies evaluated and optimized to minimize ESH impact			Novel wafer cleaning technologies implemented			

Manufacturable solutions exist, and are being optimized Manufacturable solutions are known Interim solutions are known Manufacturable solutions are NOT known





Process and Equipment Technology Requirements

Table ESH4a Process and Equipm Develop eco-design criteria,

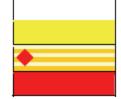
* The Environment, Safety, and Health new chemical scre

* The Environment, Safety, and Hea	^{ilth new chemical scree} establish m	etrics and targets for
Year of Production	2007	2014 2015
New Equipment Design	minimized e	environmental
Eco-design	Develop en footprint an metros and ta environmental footprint and impact.	d impact.
Design for Maintenance	Develop safe maintenance criteria.	Design equipment so that commonly serviced components and
Energy Consumption (kWh per cm2) [1]	Characterize energy requirements for process and ancillary equipment.	Characterize water and utilities requirements for
Water and other utilities (liters or m3 / em2) [1]	Characterize water and utilities requirements for process consumption. Determine leas, water recycle/reclaim; reduce water and utilities requirements 15% per technology node	process. Optimize consumption. Determine feasibility for water
Chemicals (gms/cm2) [1]	Conduct ESH risk assessment of processes and equipment.	recycle/reclaim; reduce water and utilities
Consumables**	Establish consumables baseline.	requirements 15% per
Equipment thermal management	Establish baseline	F technology node. equipment to cleanroom air by 15% from baseline by additional 15%

Manufacturable solutions exist, and are being optimized Manufacturable solutions are known

Interim solutions are known

Manufacturable solutions are NOT known



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rm Years

Facilities, Energy & Water Technology Requirements Develop facilities to minimize

Year of Production	2007	2008 envi	ronmental footprint	2014	2015				
Facilities Design		impa	act.						
Eco-friendly facility design		ines to minimize footprint and impact	Meet a recognized standard for design						
Design for end-of-life re- use	potential re-us	d and implement se scenarios during ity design	Meet a recognized standard for reduced environmental						
Water			impact thr	ough b	uilding	re-			
Total fab* water consumption (liters/cm ²) [1]		14	use; e.g., l						
Total site water consumption reduction	Establish baseline	Reduce total consumption 10% from baseline levels	Reduce total consumption additional 10%	Reduce tota	total consumption additional 10%				
Total UPW consumption (liters/cm ²) [1]		8	7						
UPW recycled/reclaimed** (% of use)		70	75						
Energy (electricity, natural	gas, etc.)								
Total fab* energy consumption (kWh per cm ²) [1]		1.9	1.6	1.35					
Total site energy consumption reduction	Establish baseline	Reduce total consumption 10% from baseline levels	Reduce total consumption additional 10%			And ditional			
Cleanroom thermal management	Establ	sh baseline	Reduce heat rejection from process and ancillary equipment to cleanroom air by 15% from baseline	and ancillary equip					

Sustainability and Product Stewardship

Year of Production	2007	2008	2009				2019	2020	2021	2022	
Sustainability Metrics				Develop	key enviroi	nmental					
Facilities Eco-design	criteri metrics minimiza	lop eco-de ia, establis s and targ ed enviror rint and in	shing ets for nmental	(KEPIs) and establish				ental footprint, and safety and			
Carbon footprint		ommon me ablish basel		baseline.							
Product Eco-design	Develop key environmer performance indicators (KEPIs)* and establish baseline						Reduce KEPIs* additional 10%				
Design for ESH											
Materials	Develop key environmental performance indicators (KEPIs)* and establish baseline		performance indicators Reduce KEPIs* 10% Reduce KEPIs* Reduce KEPIs*			Reduce KEPIs* additional 109			al 10%		
				of ESH impacts during the v			impared a	nd selecte	ed)		
-	perfor	key enviro mance indi	cators	Reduce KEPIs* 10% from baseline levels	Reduce KEPIs* additional 10%	Reduce KEPIs* additional 10%	Reduce KEPIs* additional 10			al 10%	
Processes	(KEPI	s)* and est baseline		Alternative low-ESH i planarization a	ind deposition		hift to additive processing				
Improved integration of ESH into factory and equipment design				of ESH impacts during the v ESH design guidelines, m					ed)		
End-of-Life											
Ease of decommissioning and decontamination for facility re-use/re- claim	impleme	nprehend nt potentia ios during design	al re-use	Reduce environmental i design fo	tal impact through building design for re-use			Ĩ			
Ease of decommissioning and decontamination for equipment re- use/re-claim Slide 29				Design process and and	illary equipment for disas	sembly and re-use/recla	iim		UFACTURIN	M	

Potential Solutions

- Nanomaterial risk assessment methodology and tools development
- Integrate Key Environmental Performance Indicators into materials selection
- Additive processing
- Imprint patterning for advanced technology nodes
- Alternative low-ESH impact processes for planarization
- Alternative 3-D etch processes
- High efficiency rinses
- Real-time, on-line, speciating sensors for UPW
 recycle



Addressing ESH During Technology Development

- Early ESH risk information on R&D materials and processes is important to
 - Prevent potential ESH showstoppers (ensures materials with regulatory bans and policy bans are not being introduced)
 - Minimize negative impacts and costs
 - Minimize future potential ESH liability
 - Avoid potential delays in process implementation due to ESH issues/risks
 - Allow for greater flexibility in considering technology options and making strategic business decisions



Final Thoughts

- From "Beyond The Green Corporation," January 29, 2007, *Business Week* cover story:
 - Assets of socially responsible mutual funds increased
 - \$12 billion in 1995
 - \$178 billion in 2005
 - Sustainability factors "...show that companies tend to be more strategic, nimble, and better equipped to compete in the complex, highvelocity global environment."

